

Amendment and Response

Applicant: Irwin Aberin et al.

Serial No.: 10/588,927

Filed: August 3, 2007

Docket No.: 1431.168.101/FIN581PCT/US

Title: SEMICONDUCTOR PACKAGE WITH PERFORATED SUBSTRATE

IN THE CLAIMS

Please amend claims 17, 22-25, 30, 32, and 33 as follows:

1-16 (cancelled)

17. (Currently Amended) A method to assemble a substrate for a semiconductor package comprising:

providing a substrate comprising a sheet of core material and a plurality of upper contact traces and upper contact pads on its upper surface, a second plurality of lower conducting traces and external contact areas on its bottom surface and conducting vias connecting the upper conducting traces and lower conducting traces;

forming a plurality of non-plated vent holes in the substrate in an area in which a semiconductor chip will be mounted to the upper surface and in areas of the substrate which will be adjacent to the area in which the semiconductor chip will be mounted; and

covering the upper and lower surfaces of the substrate by a layer of solder resist leaving the contact areas free from solder resist.

18. (Previously Presented) The method to assemble a substrate of claim 17, wherein the vent holes are closed at one end by a layer of solder resist on the upper surface of the substrate.

19. (Previously Presented) The method to assemble a substrate of claim 17, wherein the vent holes include solder resist.

20. (Previously Presented) The method to assemble a substrate of claim 17, wherein the vent holes are formed by drilling.

Amendment and Response

Applicant: Irwin Aberin et al.

Serial No.: 10/588,927

Filed: August 3, 2007

Docket No.: I431.168.101/FIN581PCT/US

Title: SEMICONDUCTOR PACKAGE WITH PERFORATED SUBSTRATE

21. (Previously Presented) The method to assemble a substrate of claim 17, further comprising forming the vent holes in the core material before a plurality of upper contact traces and upper contact pads on its upper surface, a second plurality of lower conducting traces and external contact areas on its bottom surface and depositing conducting vias.

22. (Currently Amended) A method to assemble a semiconductor package comprising: providing a substrate comprising a sheet of core material and a plurality of upper contact traces and upper contact pads on its upper surface, a second plurality of lower conducting traces and external contact areas on its bottom surface and conducting vias connecting the upper conducting traces and lower conducting traces;

forming a plurality of non-plated vent holes in the substrate;

covering the upper and lower surfaces of the substrate by a layer of solder resist leaving the contact areas free from solder resist;

providing a semiconductor chip comprising an active surface including a plurality of chip contact areas;

mounting the chip on the upper surface of the redistribution board by microscopic solder balls between the chip contacts and upper contact areas, wherein non-plated vent holes are distributed below and adjacent to the semiconductor chip;

performing a solder reflow; and

underfilling the area between the chip and the upper surface of the redistribution board with epoxy resin.

23. (Currently Amended) A method to assemble a semiconductor package characterized in that The method of claim 22, including covering the upper surface of the chip and substrate are covered with mold material.

24. (Currently Amended) A substrate for a semiconductor package comprising: a sheet of core material;

Amendment and Response

Applicant: Irwin Aberin et al.

Serial No.: 10/588,927

Filed: August 3, 2007

Docket No.: I431.168.101/FIN581PCT/US

Title: SEMICONDUCTOR PACKAGE WITH PERFORATED SUBSTRATE

a plurality of upper conducting traces and upper contact pads on an upper surface of the sheet, a second plurality of lower conductive traces and external contact areas on a bottom surface of the sheet and a plurality of conducting vias connecting the upper conducting traces and lower conducting traces;

a plurality of non-plated vent holes in the substrate in an area in which a semiconductor chip will be mounted to the upper surface and in areas of the substrate which will be adjacent to the area in which the semiconductor chip will be mounted; and

a layer of solder resist covering the upper and lower surfaces of the substrate leaving the contact areas free from solder resist.

25. (Currently Amended) The substrate of claim 24, wherein the vent holes are include solder resist.

26. (Previously Presented) The substrate of claim 24, wherein the vent holes are closed at one end by a layer of solder resist on the upper surface of the substrate.

27. (Previously Presented) The substrate of claim 24, wherein the plurality of vent holes are laterally located towards the center of the substrate.

28. (Previously Presented) The substrate of claim 24, wherein the plurality of vent holes are laterally located towards the center and towards the outer edges of the substrate.

29. (Previously Presented) The substrate of claim 24, wherein the vent holes have a diameter of approximately 1 μ m to approximately 5mm or approximately 10 μ m to approximately 0.5mm or approximately 100 μ m.

30. (Currently Amended) A semiconductor package comprising:
a sheet of core material;

Amendment and Response

Applicant: Irwin Aberin et al.

Serial No.: 10/588,927

Filed: August 3, 2007

Docket No.: I431.168.101/FIN581PCT/US

Title: SEMICONDUCTOR PACKAGE WITH PERFORATED SUBSTRATE

a plurality of upper conducting traces and upper contact pads on an upper surface of the sheet, a second plurality of lower conductive traces and external contact areas on a bottom surface of the sheet and a plurality of conducting vias connecting the upper conducting traces and lower conducting traces;

a plurality of non-plated vent holes through the sheet;

a layer of solder resist covering the upper and lower surfaces of the substrate sheet leaving the contact areas free from solder resist; and

a substrate; and

a semiconductor chip including an active surface with a plurality of chip contact areas, electrically connected to the substrate sheet, wherein non-plated vent holes are distributed below and adjacent to the semiconductor chip.

31. (Previously Presented) The semiconductor package of claim 30, wherein the chip is encapsulated by mold material.

32. (Currently Amended) The semiconductor package of claim 30, wherein the chip is mounted to the substrate sheet by the flip-chip technique.

33. (Currently Amended) A substrate for a semiconductor package comprising:

a sheet of core material with an upper surface and a bottom surface each covered with a layer of solder resist;

a plurality of upper conducting traces and upper contact pads on the upper surface;

a plurality of bottom conductive traces and external contact areas on the bottom surface;

a plurality of conducting vias connecting the upper conducting traces and bottom conducting traces;

a plurality of non-plated vent holes through sheet in a chip mounting area on the sheet where a semiconductor chip will be mounted to the upper surface and in areas adjacent to the chip mounting area; and

Amendment and Response

Applicant: Irwin Aberin et al.

Serial No.: 10/588,927

Filed: August 3, 2007

Docket No.: I431.168.101/FIN581PCT/US

Title: SEMICONDUCTOR PACKAGE WITH PERFORATED SUBSTRATE

~~means for leaving the contact areas free from a layer of solder resist covering the upper and bottom surfaces except for the contact areas.~~

34. (Previously Presented) The substrate of claim 33, wherein the vent holes include solder resist.

35. (Previously Presented) The substrate of claim 33, wherein the vent holes are closed at one end by a layer of solder resist on the upper surface of the substrate.

36. (Previously Presented) The substrate of claim 33, wherein the plurality of vent holes are laterally located towards the center of the substrate.